MAY 1 4 2003

TRADEMINAMENDMENT TRANSMITTAL LETTER						Docket No. SON-1745	
Application No. 09/512,336-Conf. #5387		Filing Date February 24, 2000		Examiner K. Chen		Art Unit 1765	
Applicant(s): Seiid		: t.	,				
Invention: DRY E		HOD AND MET	THOD OF MA	NUFACTURING S	EMICON	DUCTOR	
TO THE COMMISSIONER FOR PATENTS							
Transmitted herewith is an amendment in the above-identified application. The fee has been calculated and is transmitted as shown below.						REC.	
CLAIMS AS AMENDED							
	Claims Remaining After Amendment	Highest Number Previously Paid	Number Extra Claims Present	Rate		RECEIVED MAY 15 2003 1700 MAII BOOM	
Total Claims	4	- 20 =		×		0.00	
Independent Claims	2	- 3 =		×		0.00	
Multiple Dependent Claims (check if applicable)							
Other fee (please specify):							
TOTAL ADDITIONAL FEE FOR THIS AMENDMENT:						0.00	
x Large Entity Small Entity							
x No additional fee is required for this amendment.							
Please charge Deposit Account No in the amount of \$ A duplicate copy of this sheet is enclosed.							
A check in the amount of \$ to cover the filing fee is enclosed.							
Payment by credit card. Form PTO-2038 is attached.							
as described	ssioner is heret I below. A dup ny overpaymer	licate copy of		credit Deposit Acco	ount No.	18-0013	
= $/$ $/$			n processing	fees required under 3	7 CFR 1.	16 and 1.17.	
Ronald B. Kananen Reg. 24,104 Dayld K. Benson Reg. 42,314						, 2003	
RADER, FISHM 1233 20th Stree Suite 501 Washington, DO (202) 955-3750	et, N.W. C 20036	R PLLC					



Docket No.: SON-1745 5/157 (PATENT)

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of:

Seiichi Fukuda

Application No.: 09/512,336

Filed: February 24, 2000

For: DRY ETCHING METHOD AND METHOD OF

MANUFACTURING SEMICONDUCTOR

APPARATUS

Group Art Unit: 1765

Examiner: K. Chen

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AMENDMENT

Box Non-Fee Amendment Commissioner for Patents Washington, DC 20231

Dear Sir:

In response to the Office Action dated February 14, 2003 (Paper No. 21), please amend the above-identified U.S. patent application as follows: